

Notice of References Cited	Application/Control No. 10/790,030	Applicant(s)/Patent Under Reexamination AOKI ET AL	
	Examiner EDMUND H. LEE	Art Unit 1732	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,522,417	06-1996	Tomioka et al.	137/43
*	B	US-6,484,741	11-2002	Benjey et al.	137/15.26
*	C	US-6,382,231	05-2002	Sugizaki et al.	137/15.26
*	D	US-6,502,607	01-2003	Brown et al.	141/1
*	E	US-6,408,867	06-2002	Aoki et al.	137/202
*	F	US-5,139,043	08-1992	Hyde et al.	137/43
*	G	US-6,464,920	10-2002	Kramer, Hans	264/243
*	H	US-2001/0047822	12-2001	Aoki et al.	137/202
*	I	US-2004/0119200	06-2004	Gram, Jes Tougaard	264/255
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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